

**Search Notes**

Application/Control No.

10/509,231

Examiner

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Applicant(s)/Patent under  
Reexamination

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Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
370	342	4/30/2007	IAK
455	452.2	4/30/2007	IAK
455	450	4/30/2007	IAK
370	252	4/30/2007	IAK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EASTImage and keyword search in USPAT, US-PGPUB, DERWENT, EPO, IBM_TDB (see attached search strategy)	4/30/2007	IAK